Search Notes

| Application/Control No. | Applicant(s)/Patent under Reexamination |                   |  |
|-------------------------|---|-------------------|--|
| 09/955,146              | TERASAKI, HIROSHI                       | TERASAKI, HIROSHI |  |
| Examiner                | Art Unit                                |                   |  |
| Ashutosh Upreti         | 2623                                    |                   |  |

| SEARCHED   |  |          |          |  |  |
|------------|--|----------|----------|--|--|
| Class      | Subclass                                   | Date     | Examiner |  |  |
| 382        | 100, 298,<br>299, 240,<br>302, 305,<br>232 | 09/29/04 | A.4.     |  |  |
| 709        | 203  | 9/29/64  | A.U.     |  |  |
| 705        | 57   | 9/29/04  | A.u.     |  |  |
| 705<br>713 | 176  | 9/29/04  | A.U.     |  |  |
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| INTERFERENCE SEARCHED |          |      |          |  |
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| Class                 | Subclass | Date | Examiner |  |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY)  |          |       |  |  |
|---|----------|-------|--|--|
|   | DATE     | EXMR  |  |  |
| Talked to Jon Chang:<br>Search: 382/100, 298,299<br>+ IEEE (NPL)  | 9/29/04  | A-41. |  |  |
| Talked to Andy Johns:<br>Search: 382/100,232<br>709,713/176<br>705  | 9/29/04  | A.u.  |  |  |
| Talked to Wenpeny Chen<br>Search: 382/240,302,305<br>709  | 9/29/04  | Ą.u.  |  |  |
| STIC Searched NPL for watermark in lownes-<br>olution & part of high resolution image                       | 10/26/04 | A.u.  |  |  |
| STIC searched for: output of high resolution data if watermark detected, else output of low resolution data | 11/03/04 | A·u.  |  |  |
| conducted search in<br>EAST-see search<br>history<br>(including EPO, JPO, Derwent)                          | 11/22/04 | A·U.  |  |  |
| Searched IEEE Xplore<br>for "watermark (and)<br>resolution"   | 11/22/04 | A.u.  |  |  |
|   |          |       |  |  |